ATTY. DOCKET 07977/15000

36/3421

APPLICANT: Shunpei Yamazaki, et al.

SERIAL NO. 08/855,818

Sheet

INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)

FILING DATE May 12, 1997 GROUP -2879 2881

(37 CFR 1.98(b))

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EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Substitute Disclosure Form (PTO-1449)

Sheet	1	of	1

Substitute Form PTO-1449 (Modified)

(37 CFR §1.98(b))

U.S. Department of Commerce Patent and Trademark Office

Attorney's Docket No. 07977/150003/US3336/3421D1D1

Application No. 09/696,863

Information Disclosure Statement by Applicant

(Use several sheets if necessary)

Yamazaki, et al.

Filing Date

Applicant

October 25, 2000

Group Art Unit 2881

			U.S. Paten	t Documents			
Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
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14.0	AL	04-160745	6/4/92	Japan			Abstract only	
1445	AM	06-291073	10/18/94	Japan		-	Abstract	
US	AN	07-007060	1/31/95	Japan			Concise Statement	
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.		Other Do	ocuments (include Author, Title, Date, and Place of Publication)
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